

CoolMOS™ Power Transistor
Product Summary
Features

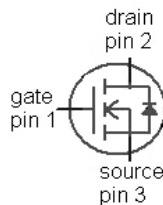
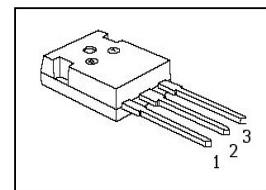
- Worldwide best $R_{ds(on)}$ in TO247
- Ultra low gate charge
- Extreme dv/dt rated
- High peak current capability
- Qualified according to JEDEC¹⁾ for target applications
- Pb-free lead plating; RoHS compliant

$V_{DS} @ T_{jmax}$	650	V
$R_{DS(on),max}$	0.045	Ω
$Q_{g,typ}$	150	nC

PG-T0247-3-1

CS CoolMOS is specially designed for:

- Hard switching SMPS topologies



Type	Package	Ordering Code	Marking
IPW60R045CP	PG-T0247-3-1	SP000067149	6R045

Maximum ratings, at $T_j=25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	$T_C=25^\circ\text{C}$	60	A
		$T_C=100^\circ\text{C}$	38	
Pulsed drain current ²⁾	$I_{D,pulse}$	$T_C=25^\circ\text{C}$	230	
Avalanche energy, single pulse	E_{AS}	$I_D=11\text{ A}, V_{DD}=50\text{ V}$	1950	mJ
Avalanche energy, repetitive $t_{AR}^{2,3)}$	E_{AR}	$I_D=11\text{ A}, V_{DD}=50\text{ V}$	3	
Avalanche current, repetitive $t_{AR}^{2,3)}$	I_{AR}		11	A
MOSFET dv/dt ruggedness	dv/dt	$V_{DS}=0\ldots480\text{ V}$	50	V/ns
Gate source voltage	V_{GS}	static	± 20	V
		AC ($f>1\text{ Hz}$)	± 30	
Power dissipation	P_{tot}	$T_C=25^\circ\text{C}$	431	W
Operating and storage temperature	T_j, T_{stg}		-55 ... 150	°C
Mounting torque		M3 and M3.5 screws	60	Ncm

Maximum ratings, at $T_j=25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current	I_S	$T_c=25\text{ }^\circ\text{C}$	44	A
Diode pulse current ²⁾	$I_{S,pulse}$		230	
Reverse diode dv/dt ⁴⁾	dv/dt		15	V/ns

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R_{thJC}		-	-	0.29	K/W
Thermal resistance, junction - ambient	R_{thJA}	leaded	-	-	62	
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	1.6 mm (0.063 in.) from case for 10 s	-	-	260	°C

Electrical characteristics, at $T_j=25\text{ }^\circ\text{C}$, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{ V}, I_D=250\text{ }\mu\text{A}$	600	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=3\text{ mA}$	2.5	3	3.5	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=600\text{ V}, V_{GS}=0\text{ V}, T_j=25\text{ }^\circ\text{C}$	-	-	10	μA
		$V_{DS}=600\text{ V}, V_{GS}=0\text{ V}, T_j=150\text{ }^\circ\text{C}$	-	50	-	
Gate-source leakage current	I_{GSS}	$V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{ V}, I_D=44\text{ A}, T_j=25\text{ }^\circ\text{C}$	-	0.04	0.045	Ω
		$V_{GS}=10\text{ V}, I_D=44\text{ A}, T_j=150\text{ }^\circ\text{C}$	-	0.11	-	
Gate resistance	R_G	$f=1\text{ MHz, open drain}$	-	1.3	-	Ω

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic characteristics

Input capacitance	C_{iss}	$V_{GS}=0 \text{ V}, V_{DS}=100 \text{ V}, f=1 \text{ MHz}$	-	6800	-	pF
Output capacitance	C_{oss}		-	320	-	
Effective output capacitance, energy related ⁵⁾	$C_{o(er)}$	$V_{GS}=0 \text{ V}, V_{DS}=0 \text{ V}$ to 480 V	-	310	-	
Effective output capacitance, time related ⁶⁾	$C_{o(tr)}$		-	820	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=400 \text{ V}, V_{GS}=10 \text{ V}, I_D=44 \text{ A}, R_G=3.3 \Omega$	-	30	-	ns
Rise time	t_r		-	20	-	
Turn-off delay time	$t_{d(off)}$		-	100	-	
Fall time	t_f		-	10	-	
Gate Charge Characteristics						

Gate Charge Characteristics

Gate to source charge	Q_{gs}	$V_{DD}=400 \text{ V}, I_D=44 \text{ A}, V_{GS}=0 \text{ to } 10 \text{ V}$	-	34	-	nC
Gate to drain charge	Q_{gd}		-	51	-	
Gate charge total	Q_g		-	150	190	
Gate plateau voltage	$V_{plateau}$		-	5.0	-	

Reverse Diode

Diode forward voltage	V_{SD}	$V_{GS}=0 \text{ V}, I_F=44 \text{ A}, T_j=25 \text{ }^\circ\text{C}$ $V_R=400 \text{ V}, I_F=I_S, di_F/dt=100 \text{ A}/\mu\text{s}$	-	0.9	1.2	V
Reverse recovery time	t_{rr}		-	600	-	ns
Reverse recovery charge	Q_{rr}		-	17	-	μC
Peak reverse recovery current	I_{rrm}		-	60	-	A

¹⁾ J-STD20 and JESD22

²⁾ Pulse width t_p limited by $T_{j,max}$
³⁾ Repetitive avalanche causes additional power losses that can be calculated as $P_{AV}=E_{AR} \cdot f$.

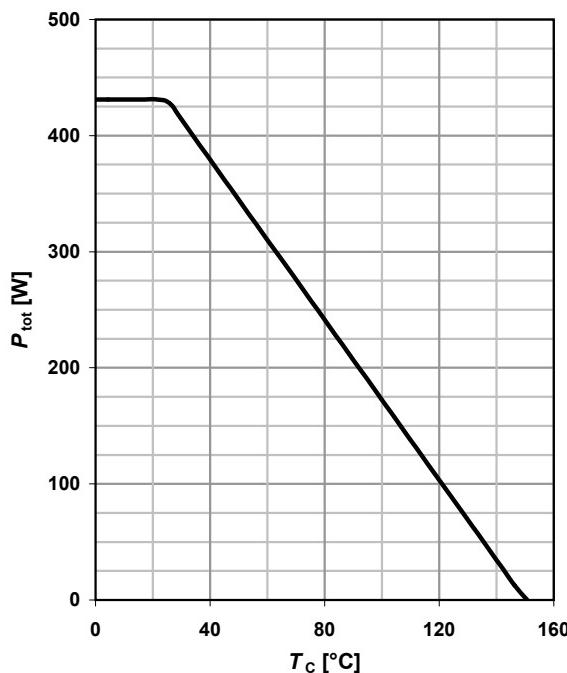
⁴⁾ $I_{SD} \leq I_D$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DClink} = 400 \text{ V}$, $V_{peak} \leq V_{(BR)DSS}$, $T_j < T_{j,max}$, identical low side and high side switch

⁵⁾ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

⁶⁾ $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

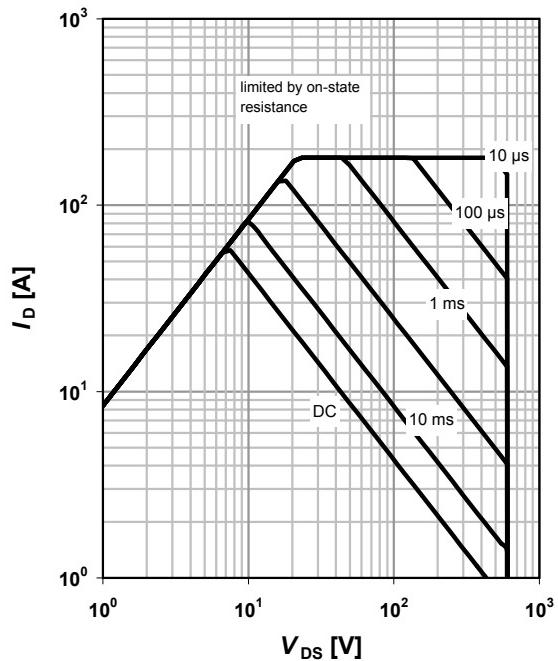
1 Power dissipation

$$P_{\text{tot}} = f(T_c)$$


2 Safe operating area

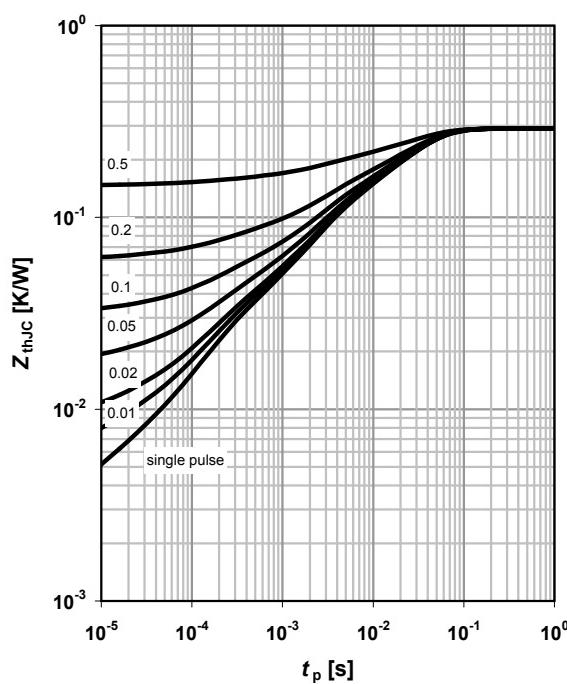
$$I_D = f(V_{DS}); T_c = 25^\circ\text{C}; D = 0$$

parameter: t_p


3 Max. transient thermal impedance

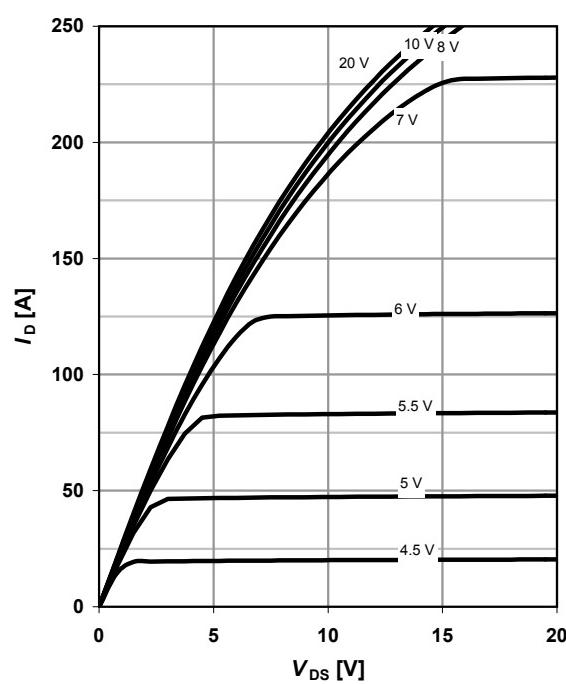
$$Z_{(\text{thJC})} = f(t_p)$$

parameter: $D = t_p/T$

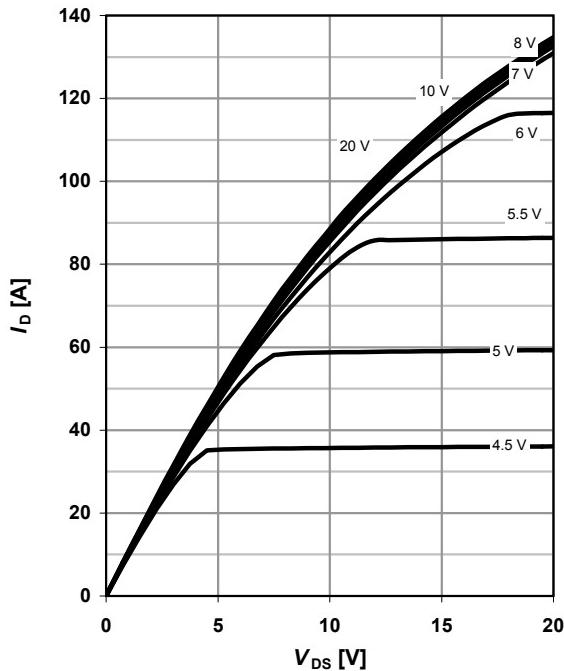

4 Typ. output characteristics

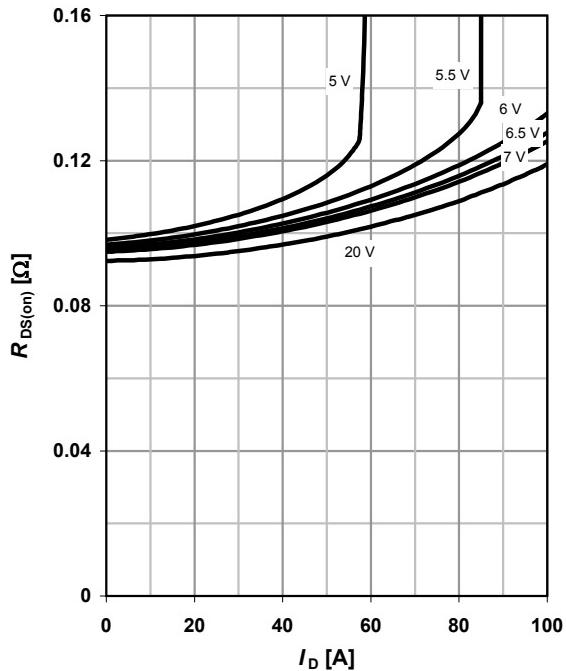
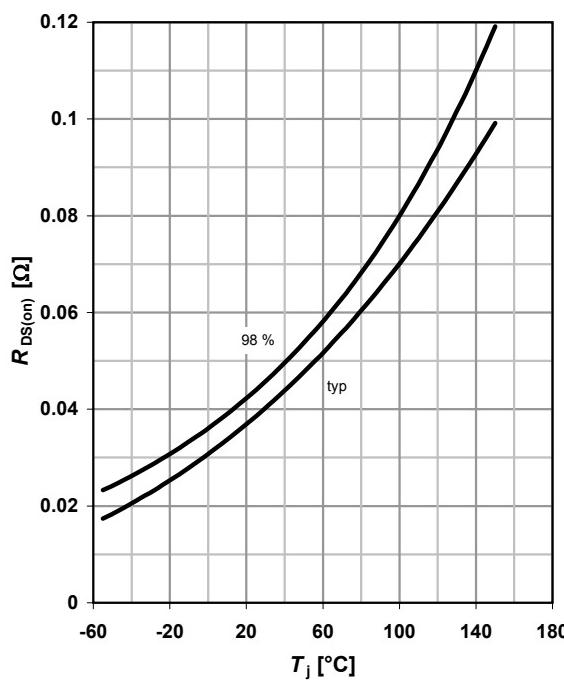
$$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$$

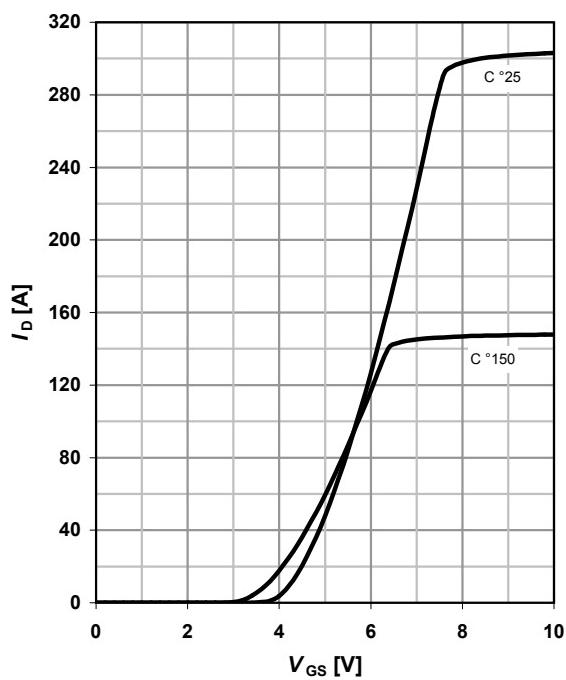
parameter: V_{GS}



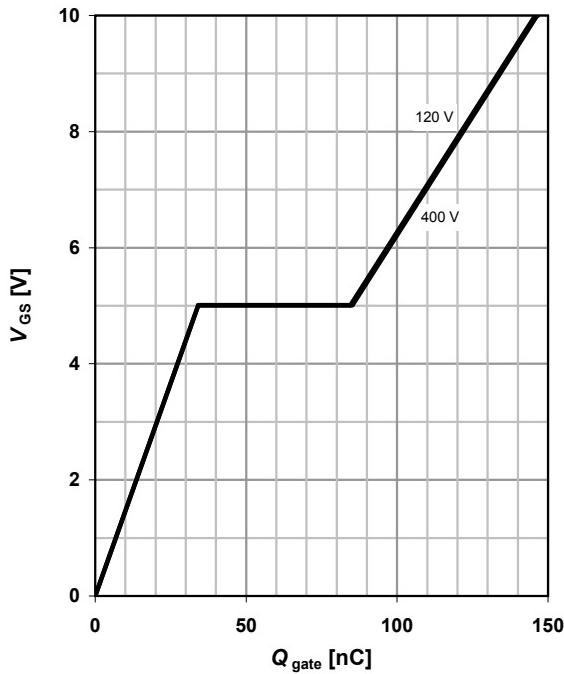
5 Typ. output characteristics
 $I_D = f(V_{DS})$; $T_j = 150 \text{ }^\circ\text{C}$

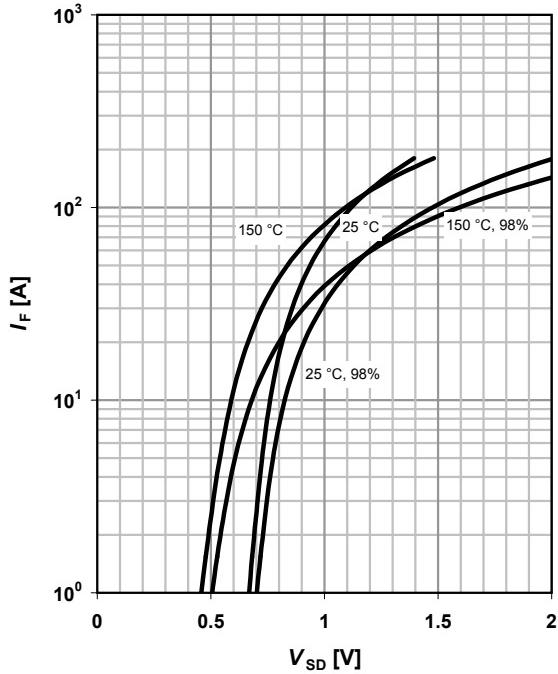
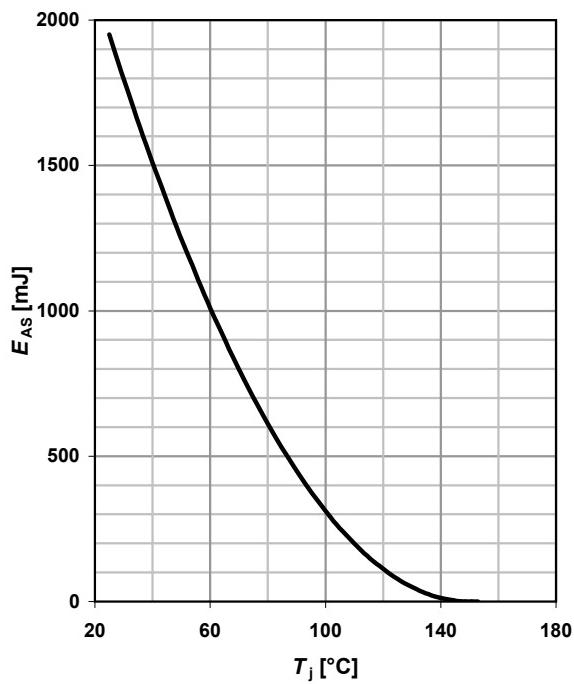
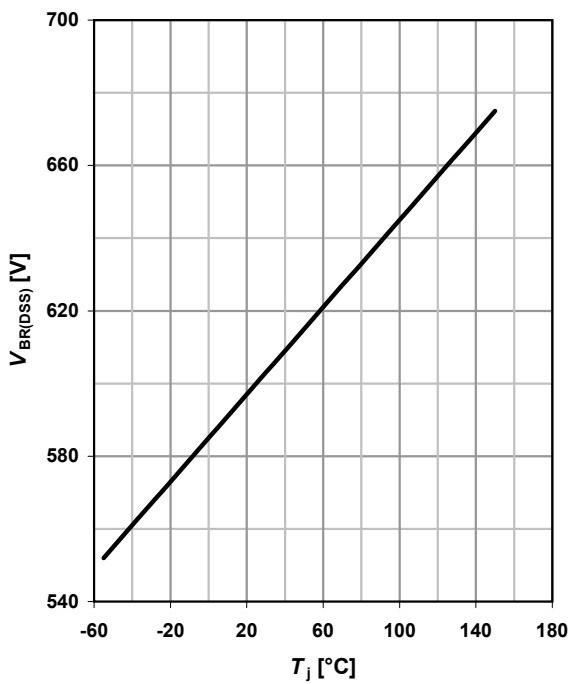
parameter: V_{GS}

6 Typ. drain-source on-state resistance
 $R_{DS(on)} = f(I_D)$; $T_j = 150 \text{ }^\circ\text{C}$

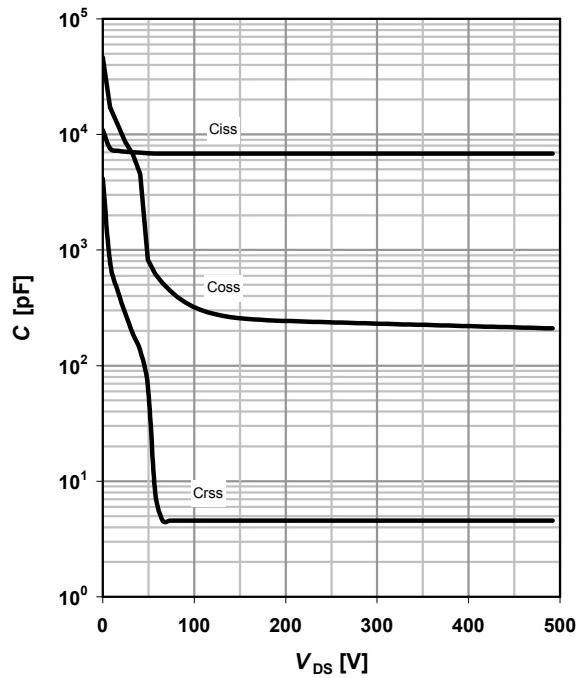
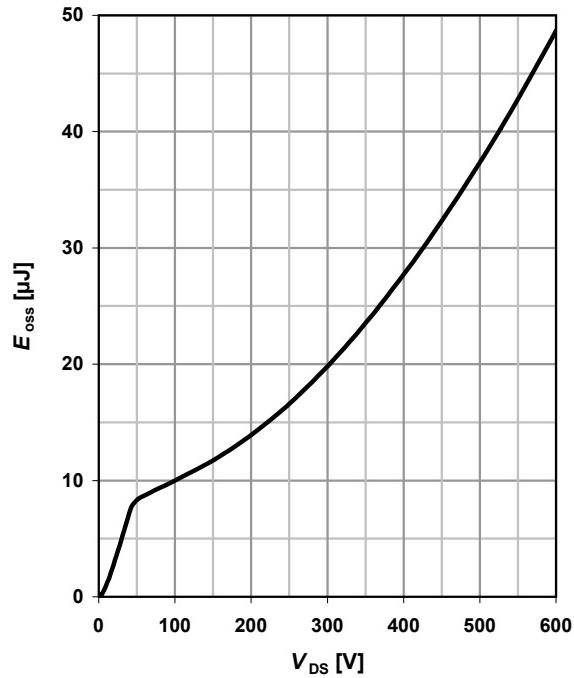
parameter: V_{GS}

7 Drain-source on-state resistance
 $R_{DS(on)} = f(T_j)$; $I_D = 44 \text{ A}$; $V_{GS} = 10 \text{ V}$

8 Typ. transfer characteristics
 $I_D = f(V_{GS})$; $|V_{DS}| > 2|I_D|R_{DS(on)max}$

parameter: T_j


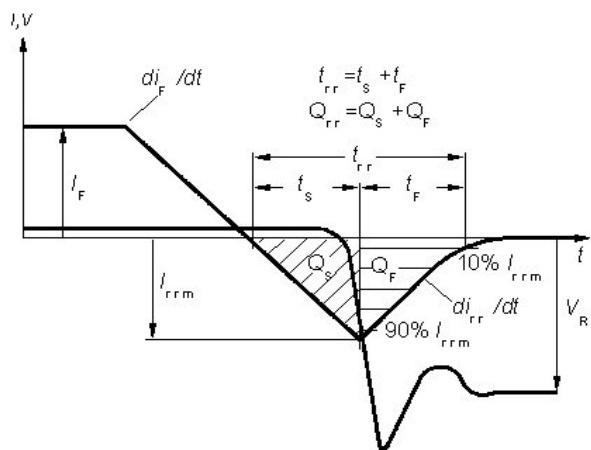
9 Typ. gate charge
 $V_{GS} = f(Q_{gate})$; $I_D = 44 \text{ A}$ pulsed

parameter: V_{DD}

10 Forward characteristics of reverse diode
 $I_F = f(V_{SD})$

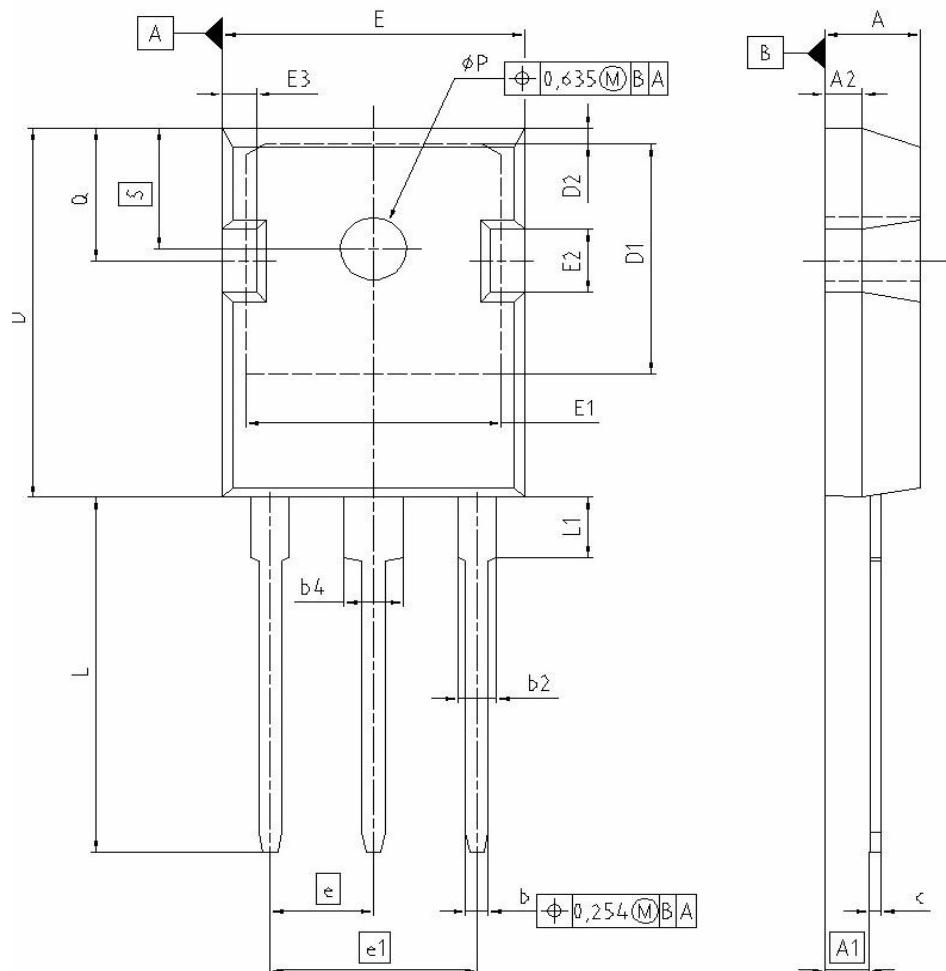
parameter: T_j

11 Avalanche energy
 $E_{AS} = f(T_j)$; $I_D = 11 \text{ A}$; $V_{DD} = 50 \text{ V}$

12 Drain-source breakdown voltage
 $V_{BR(DSS)} = f(T_j)$; $I_D = 0.25 \text{ mA}$


13 Typ. capacitances
 $C=f(V_{DS})$; $V_{GS}=0$ V; $f=1$ MHz

14 Typ. Coss stored energy
 $E_{oss}=f(V_{DS})$


Definition of diode switching characteristics



PG-T0-247-3-1: Outlines



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.903	5.157	0.193	0.203
A1	2.273	2.527	0.092	0.096
A2	1.853	2.107	0.075	0.081
b	1.073	1.327	0.047	0.052
b2	1.903	2.386	0.075	0.094
b4	2.870	3.454	0.113	0.136
c	0.549	0.752	0.024	0.030
D	20.823	21.077	0.820	0.830
D1	17.323	17.831	0.682	0.702
D2	1.063	1.317	0.042	0.052
E	15.773	16.027	0.621	0.631
E1	13.893	14.147	0.547	0.557
E2	3.683	3.937	0.145	0.155
E3	1.663	1.937	0.066	0.076
e	5.450		0.215	
e1	10.900		0.430	
N	3		3	
L	20.053	20.307	0.789	0.799
L1	4.168	4.472	0.164	0.176
ϕP	3.559	3.661	0.140	0.144
Q	5.493	5.747	0.216	0.226
S	6.043	6.297	0.238	0.248

REFERENCE	JEDEC TO247-AD
SCALE	0 0 5 5 7.5mm
EUROPEAN PROJECTION	
ISSUE DATE	28-06-2005
FILE	TO247_1

Dimensions in mm/inches:

Published by
Infineon Technologies AG
81726 München, Germany
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